

Notice of References Cited	Application/Control No. 10/735,701	Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner B. William Baumeister	Art Unit 2815	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,864,171	01-1999	Yamamoto et al.	257/628
	B	US-6,281,524	08-2001	Yamamoto et al.	257/99
	C	US-5,627,109	05-1997	Sassa et al.	438/460
	D	US-2002/0063258	05-2002	MOTOKI, KENSAKU	257/95
	E	US-2001/0030328	10-2001	Ishida, Masahiro	257/103
	F	US-6,307,218	10-2001	Steigerwald et al.	257/99
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-177146	06-2001	Japan	Tadatomo et al.	H01L 33/00
	O	JP 11-340576	12-1999	Japan	Motoki et al.	H01L 33/00
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lee et al., "Efficiency improvement in light-emitting diodes based on geometrically deformed chips," Proceedings of SPIE, Light-Emitting Diodes: Research, Manufacturing, and Applications III; Schubert et al. Eds., 27-28 Jan. 1999, Vol. 3621, pp. 237-248.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.